256Mb H-die DDR SDRAM Specification

66 TSOP-II with Pb-Free (RoHS compliant)

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Revision History

Revision	Month	Year	History
0.0	July	2005	- First version for internal review
0.1	August	2005	- Deleted x4 DDR333 speed.
1.0	November	2005	- Revision 1.0
1.1	February	2006	- Updated overshoot/undershoot specification & input slew rate for DDR333/400 speed
1.2	January	2007	 Revised overshoot/undershoot specification following JEDEC SPEC Added tPDEX on AC parameter specification

1.0 Key Features

- VDD : 2.5V ± 0.2V, VDDQ : 2.5V ± 0.2V for DDR266, 333
- VDD : 2.6V \pm 0.1V, VDDQ : 2.6V \pm 0.1V for DDR400
- Double-data-rate architecture; two data transfers per clock cycle
- Bidirectional data strobe [DQS] (x4,x8) & [L(U)DQS] (x16)
- Four banks operation
- Differential clock inputs(CK and \overline{CK})
- DLL aligns DQ and DQS transition with CK transition
- MRS cycle with address key programs
 - -. Read latency : DDR266(2, 2.5 Clock), DDR333(2.5 Clock), DDR400(3 Clock)
 - -. Burst length (2, 4, 8)
 - -. Burst type (sequential & interleave)
- All inputs except data & DM are sampled at the positive going edge of the system clock(CK)
- Data I/O transactions on both edges of data strobe
- Edge aligned data output, center aligned data input
- LDM,UDM for write masking only (x16)
- DM for write masking only (x4, x8)
- Auto & Self refresh
- 7.8us refresh interval(8K/64ms refresh)
- Maximum burst refresh cycle : 8
- 66pin TSOP II Pb-Free package
- RoHS compliant

Part No.	Org.	Max Freq.	Interface	Package	
K4H560438H-UC/LA2	64M x 4	A2(DDR266@CL=2)	SSTL2	66pin TSOP II	
K4H560438H-UC/LB0	04101 X 4	B0(DDR266@CL=2.5)		00pin 130F ii	
K4H560838H-UC/LCC		CC(DDR400@CL=3)			
K4H560838H-UC/LB3	32M x 8	B3(DDR333@CL=2.5)	SSTL2	66pin TSOP II	
K4H560838H-UC/LA2	32101 X 0	A2(DDR266@CL=2)		00011130711	
K4H560838H-UC/LB0		B0(DDR266@CL=2.5)			
K4H561638H-UC/LCC		CC(DDR400@CL=3)			
K4H561638H-UC/LB3	16M x 16	B3(DDR333@CL=2.5)	SSTL2	66pin TSOP II	
K4H561638H-UC/LA2		A2(DDR266@CL=2)	331L2		
K4H561638H-UC/LB0	1	B0(DDR266@CL=2.5)]		

2.0 Ordering Information

3.0 Operating Frequencies

	CC(DDR400@CL=3)	B3(DDR333@CL=2.5)	A2(DDR266@CL=2.0)	B0(DDR266@CL=2.5)
Speed @CL2	-	133MHz	133MHz	100MHz
Speed @CL2.5	166MHz	166MHz	133MHz	133MHz
Speed @CL3	200MHz	-	-	-
CL-tRCD-tRP	3-3-3	2.5-3-3	2-3-3	2.5-3-3



4.0 Pin Description

16Mb x 16									
32Mb x 8									
64Mb x 4									
VDD	VDD	VDD	1 (66	Ъ	Vss	Vss	Vss
DQo	DQ	NC	2		65	F	NC	DQ7	DQ 15
VDDQ	VDDQ	VDDQ	3		64	Б	Vssq	Vssq	Vssq
DQ1	NC	NC	4		63		NC	NC	DQ 14
DQ ₂	DQ1	DQo	5		62		DQ₃	DQ ₆	DQ 13
Vssq	Vssq	Vssq	6		61		VDDQ	VDDQ	VDDQ
DQ₃	NC	NC	7		60		NC	NC	DQ 12
DQ4	DQ2	NC	8		59		NC	DQ₅	DQ 11
VDDQ	VDDQ	VDDQ	9		58		Vssq	Vssq	Vssq
DQ₅	NC	NC	10	66Pin TSOPII	57		NC	NC	DQ 10
DQ6	DQ3	DQ1	11	(400mil x 875mil)	56		DQ_2	DQ4	DQ9
Vssq	Vssq	Vssq	12	(0.65mm Pin Pitch)	55		VDDQ	VDDQ	VDDQ
DQ7	NC	NC	13		54		NC	NC	DQ8
NC	NC	NC	14	Bank Address	53		NC	NC	NC
VDDQ	VDDQ	VDDQ	15	BA0~BA1	52		Vssq	Vssa	Vssq
LDQS	NC	NC	16	DAUSDAT	51		DQS	DQS	UDQS
NC	NC	NC	17	Auto Brochargo	50		NC	NC	NC
VDD	VDD	VDD	18	Auto Precharge A10	49		VREF	VREF	VREF
NC	NC	NC	19	AIU	48		Vss	Vss	Vss
LDM	NC	NC	20		47		DM	DM	UDM
WE	WE	WE	21		46		ск	СК	СК
CAS	CAS	CAS	22		45		ск	СК	СК
RAS	RAS	RAS	23		44		CKE	CKE	CKE
CS	CS	CS	24		43		NC	NC	NC
NC	NC	NC	25		42		A 12	A 12	A 12
BA ₀	BA ₀	BA ₀	26		41		A 11	A 11	A 11
BA1	BA1	BA1	27		40		A۹	A9	A۹
AP/A 10	AP/A 10	AP/A 10	28		39		A8	A 8	A8
A	Ao	A	29		38	白	A 7	A 7	A 7
A 1	A 1	A 1	30		37	Þ	A ₆	A ₆	A ₆
A 2	A 2	A 2	31		36	Þ	A5	A5	A5
A ₃	A 3	A3	32		35	þ	A 4	A 4	A 4
VDD	VDD	VDD	33		34	þ	Vss	Vss	Vss
						L			

256Mb TSOP-II Package Pinout

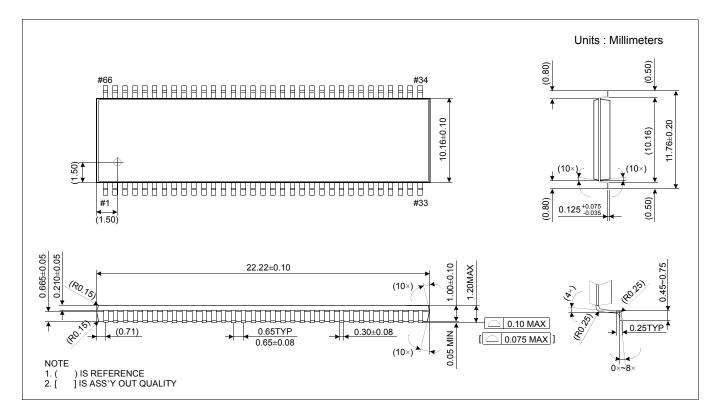
Organization	Row Address	Column Address
64Mx4	A0~A12	A0-A9, A11
32Mx8	A0~A12	A0-A9
16Mx16	A0~A12	A0-A8

DM is internally loaded to match DQ and DQS identically.

Row & Column address configuration

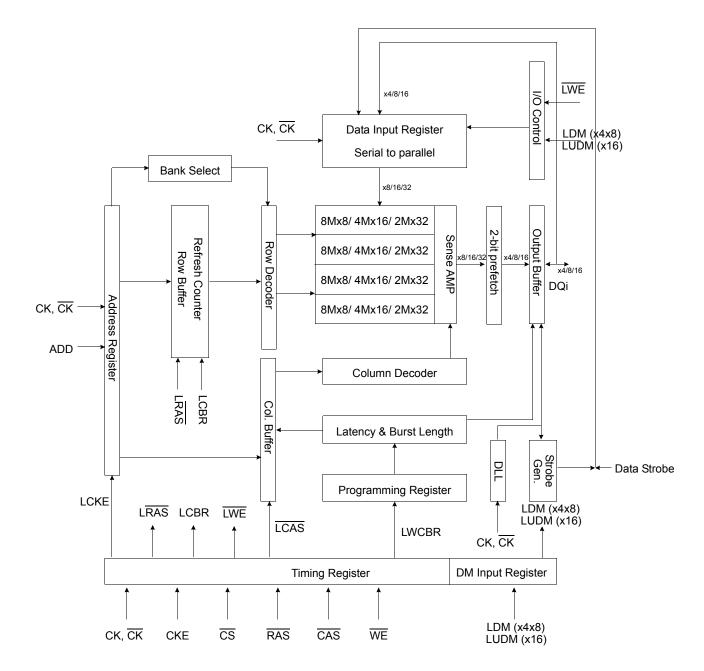


5.0 Package Physical Dimension



66pin TSOPII / Package dimension

6.0 Block Diagram (16Mb x 4 / 8Mb x 8 / 4Mb x 16 I/O x4 Banks)



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7.0 Input/Output Function Description

SYMBOL	TYPE	DESCRIPTION
CK, CK	Input	Clock : CK and \overline{CK} are differential clock inputs. All address and control input signals are sampled on the positive edge of CK and negative edge of \overline{CK} . Output (read) data is referenced to both edges of CK. Internal clock signals are derived from CK/CK.
CKE	Input	Clock Enable : CKE HIGH activates, and CKE LOW deactivates internal clock signals, and device input buffers and output drivers. Taking CKE Low provides PRECHARGE POWER-DOWN and SELF REFRESH operation (all banks idle), or ACTIVE POWER-DOWN (row ACTIVE in any bank). CKE is synchronous for POWER-DOWN entry and exit, and for SELF REFRESH entry. CKE is asynchronous for SELF REFRESH exit, and for output disable. CKE must be maintained high throughput READ and WRITE accesses. Input buffers, excluding CK, CK and CKE are disabled during POWER-DOWN. Input buffers, excluding CKE are disabled during SELF REFRESH. CKE is an SSTL_2 input, but will detect an LVCMOS Low level after Vdd is applied upon 1st power up, After $V_{\rm REF}$ has become stable during the power on and initialization sequence, it must be maintained for proper operation of the CKE receiver. For proper SELF-REFRESH entry and exit, $V_{\rm REF}$ must be maintained to this input.
CS	Input	Chip Select : \overline{CS} enables(registered LOW) and disables(registered HIGH) the command decoder. All commands are masked when \overline{CS} is registered HIGH. \overline{CS} provides for external bank selection on systems with multiple banks. \overline{CS} is considered part of the command code.
RAS, CAS, WE	Input	Command Inputs : \overline{RAS} , \overline{CAS} and \overline{WE} (along with \overline{CS}) define the command being entered.
LDM,(UDM)	Input	Input Data Mask : DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with that input data during a WRITE access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading. For the x16, LDM corresponds to the data on DQ0~D7 ; UDM corresponds to the data on DQ8~DQ15. DM may be driven high, low, or floating during READs.
BA0, BA1	Input	Bank Addres Inputs : BA0 and BA1 define to which bank an ACTIVE, READ, WRITE or PRE-CHARGE command is being applied.
A [0 : 12]	Input	Address Inputs : Provide the row address for ACTIVE commands, and the column address and AUTO PRECHARGE bit for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 is sampled during a PRECHARGE command to determine whether the PRECHARGE applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by BA0, BA1. The address inputs also provide the op-code during a MODE REGISTER SET command. BA0 and BA1 define which mode register is loaded during the MODE REGISTER SET command (MRS or EMRS).
DQ	I/O	Data Input/Output : Data bus
LDQS,(U)DQS	I/O	Data Strobe : Output with read data, input with write data. Edge-aligned with read data, cen- tered in write data. Used to capture write data. For the x16, LDQS corresponds to the data on DQ0~D7 ; UDQS corresponds to the data on DQ8~DQ15. LDQS is NC on x4 and x8.
NC	-	No Connect : No internal electrical connection is present.
VDDQ	Supply	DQ Power Supply : +2.5V \pm 0.2V. (+2.6V $\pm 0.1V$ for DDR400)
VSSQ	Supply	DQ Ground.
VDD	Supply	Power Supply : +2.5V \pm 0.2V. (+2.6V $\pm 0.1V$ for DDR400)
VSS	Supply	Ground.
VREF	Input	SSTL_2 reference voltage.

8.0 Command Truth Table

(V=Valid, X=Don't Care, H=Logic High, L=Logic Low)

COMMAND			CKEn-1	CKEn	CS	RAS	CAS	WE	BA0,1	A10/AP	A0 ~ A9, A11 ~ A12	Note
Register	Extended MRS		Н	Х	L	L	L	L		OP CODE		1, 2
Register	Mode Regist	ter Set	Н	Х	L	L	L	L		OP CC	DE	1, 2
	Auto Refrest	า	н	Н				н		Х		3
Refresh		Entry		L	L	L	L	п		Χ		3
Reliesh	Self Refresh	Exit		н	L	Н	Н	Н		Х		3
	Reneon	EXIL	L	п	Н	Х	Х	Х		Χ		3
Bank Active & Roy	w Addr.		Н	Х	L	L	Н	Н	V	Row	/ Address	
Read &	Auto Precha	rge Disable	н	х	-	н		н	V	L	Column	4
Column Address	Auto Precha	rge Enable		~	L	п	L	п	v	Н	Address	4
Write & Auto Precha Column Address Auto Precha		rge Disable		х	L	н	L	L	V	L	Column Address	4
		rge Enable	Н							Н		4, 6
Burst Stop	•		Н	Х	L	Н	Н	L		Х		7
Decelore	Bank Selecti	on	T	х			н		V	L	X	
Precharge	All Banks		Н	^	L	L	п	L	Х	<u>-</u> х		5
		Entry	н		Н	Х	Х	Х				
Active Power Dow	'n	Entry		L	L	V	V	V	1	Х		
		Exit	L	Н	Х	Х	Х	Х				
		Entry	н	L	Н	Х	Х	Х		X		
Drocherge Dewer	Down Mada	Entry		L	L	Н	Н	Н	1			
Precharge Power	Down Mode	Ev:t		н	Н	Х	Х	Х	- X			
Exit		EXIL	L	п	L	V	V	V	1			
DM(UDM/LDM for x16 only)			н			Х		•		Х		8
No operation (NO	D) · Not dofine	d		v	Н	Х	Х	Х		Х		9
No operation (NO	P) : NOT DETINE	a	Н	Х	L	Н	Н	Н	1	Х		9

Note :

1. OP Code : Operand Code. A0 ~ A12& BA0 ~ BA1 : Program keys. (@EMRS/MRS)

2. EMRS/MRS can be issued only at all banks precharge state.

A new command can be issued 2 clock cycles after EMRS or MRS.

3. Auto refresh functions are same as the CBR refresh of DRAM. The automatical precharge without row precharge command is meant by "Auto". Auto/self refresh can be issued only at all banks precharge state.

4. BA0 ~ BA1 : Bank select addresses. If both BA0 and BA1 are "I ow" at read, write, row

- If both BAo and BA1 are "Low" at read, write, row active and precharge, bank A is selected. If BAo is "High" and BA1 is "Low" at read, write, row active and precharge, bank B is selected. If BAo is "Low" and BA1 is "High" at read, write, row active and precharge, bank C is selected. If both BAo and BA1 are "High" at read, write, row active and precharge, bank D is selected.
- 5. If A10/AP is "High" at row precharge, BA0 and BA1 are ignored and all banks are selected.
- 6. During burst write with auto precharge, new read/write command can not be issued. Another bank read/write command can be issued after the end of burst. New row active of the associated bank can be issued at tRP after the end of burst.
- 7. Burst stop command is valid at every burst length.
- 8. DM(x4/8) sampled at the rising and falling edges of the DQS and Data-in are masked at the both edges (Write DM latency is 0). UDM/LDM(x16 only) sampled at the rising and falling edges of the UDQS/LDQS and Data-in are masked at the both edges (Write UDM/LDM latency is 0).
- 9. This combination is not defined for any function, which means "No Operation(NOP)" in DDR SDRAM.



16M x 4Bit x 4 Banks / 8M x 8Bit x 4 Banks / 4M x 16Bit x 4 Banks Double Data Rate SDRAM

9.0 General Description

The K4H560438H / K4H560838H / K4H561638H is 268,435,456 bits of double data rate synchronous DRAM organized as 4x 16,777,216 / 4x 8,388,608 / 4x 4,194,304 words by 4/8/16bits, fabricated with SAMSUNG's high performance CMOS technology. Synchronous features with Data Strobe allow extremely high performance up to 400Mb/s per pin. I/O transactions are possible on both edges of DQS. Range of operating frequencies, programmable burst length and programmable latencies allow the device to be useful for a variety of high performance memory system applications.

10.0 Absolute Maximum Rating

Parameter	Symbol	Value	Unit
Voltage on any pin relative to V_{SS}	V _{IN} , V _{OUT}	-0.5 ~ 3.6	V
Voltage on V_{DD} & V_{DDQ} supply relative to V_{SS}	V _{DD} , V _{DDQ}	-1.0 ~ 3.6	V
Storage temperature	T _{STG}	-55 ~ +150	٥C
Power dissipation	PD	1.5	W
Short circuit current	I _{OS}	50	mA

Note : Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded.

Functional operation should be restricted to recommend operation condition.

Exposure to higher than recommended voltage for extended periods of time could affect device reliability.

11.0 DC Operating Conditions Recommended operating conditions(Voltage referenced to Vss=0V, Ta=0 to 70°C)

Parameter	Symbol	Min	Max	Unit	Note
Supply voltage(for device with a nominal VDD of 2.5V for DDR266/333)	Vdd	2.3	2.7	V	
Supply voltage(for device with a nominal VDD of 2.6V for DDR400)	Vdd	2.5	2.7	V	
I/O Supply voltage(for device with a nominal VDD of 2.5V for DDR266/333)	Vddq	2.3	2.7	V	
I/O Supply voltage(for device with a nominal VDD of 2.5V for DDR400)	Vddq	2.5	2.7	V	
I/O Reference voltage	VREF	0.49*VDDQ	0.51*VDDQ	V	1
I/O Termination voltage(system)	V _{TT}	VREF-0.04	VREF+0.04	V	2
Input logic high voltage	VIH(DC)	VREF+0.15	Vddq+0.3	V	
Input logic low voltage	VIL(DC)	-0.3	VREF-0.15	V	
Input Voltage Level, CK and CK inputs	VIN(DC)	-0.3	VDDQ+0.3	V	
Input Differential Voltage, CK and CK inputs	VID(DC)	0.36	VDDQ+0.6	V	3
V-I Matching: Pullup to Pulldown Current Ratio	VI(Ratio)	0.71	1.4	-	4
Input leakage current	li	-2	2	uA	
Output leakage current	loz	-5	5	uA	
Output High Current(Normal strengh driver) ;V _{OUT} = V _{TT} + 0.84V	Іон	-16.8		mA	
Output High Current(Normal strengh driver) ;V _{OUT} = V _{TT} - 0.84V	IOL	16.8		mA	
Output High Current(Half strengh driver) ; $V_{OUT} = V_{TT} + 0.45V$	Іон	-9		mA	
Output High Current(Half strengh driver) ; $V_{OUT} = V_{TT} - 0.45V$	IOL	9		mA	

Note :

1. VREF is expected to be equal to 0.5*VDDQ of the transmitting device, and to track variations in the dc level of same. Peak-to peak noise on VREF may not exceed +/-2% of the dc value.

2. V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to VREF, and must track variations in the DC level of VREF

3. VID is the magnitude of the difference between the input level on CK and the input level on \overline{CK} .

4. The ratio of the pullup current to the pulldown current is specified for the same temperature and voltage, over the entire temperature and voltage range, for device drain to source voltages from 0.25V to 1.0V. For a given output, it represents the maximum difference between pullup and pulldown drivers due to process variation. The full variation in the ratio of the maximum to minimum pullup and pulldown current will not exceed 1.7 for device drain to source voltages from 0.1 to 1.0.



12.0 DDR SDRAM Spec Items & Test Conditions

Conditions	Symbol
Operating current - One bank Active-Precharge; tRC=tRCmin; tCK=10ns for DDR200, tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400; DQ,DM and DQS inputs changing once per clock cycle; address and control inputs changing once every two clock cycles.	IDD0
Operating current - One bank operation ; One bank open, BL=4, Reads - Refer to the following page for detailed test condition	IDD1
Precharge power-down standby current; All banks idle; power - down mode; CKE = <vil(max); 5ns="" 6ns="" ddr200,tck="7.5ns" ddr266,="" ddr333,="" ddr400;<br="" for="" tck="10ns">Vin = Vref for DQ,DQS and DM.</vil(max);>	IDD2P
Precharge Floating standby current; CS# > =VIH(min);All banks idle; CKE > = VIH(min); tCK=10ns for DDR200,tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400; Address and other control inputs changing once per clock cycle; Vin = Vref for DQ,DQS and DM	IDD2F
Precharge Quiet standby current; CS# > = VIH(min); All banks idle; CKE > = VIH(min); tCK=10ns for DDR200, tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400; Address and other control inputs stable at >= VIH(min) or = <vil(max); ,dqs="" and="" dm<="" dq="" for="" td="" vin="Vref"><td>IDD2Q</td></vil(max);>	IDD2Q
Active power - down standby current ; one bank active; power-down mode; CKE=< VIL (max); tCK=10ns for DDR200,tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400; Vin = Vref for DQ,DQS and DM	IDD3P
Active standby current; CS# >= VIH(min); CKE>=VIH(min); one bank active; active - precharge; tRC=tRASmax; tCK=10ns for DDR200,tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400; DQ, DQS and DM inputs changing twice per clock cycle; address and other control inputs changing once per clock cycle	IDD3N
Operating current - burst read; Burst length = 2; reads; continguous burst; One bank active; address and control inputs changing once per clock cycle; CL=2 at tCK=10ns for DDR200, CL=2 at 7.5ns for DDR266(A2), CL=2.5 at tCK=7.5ns for DDR266(B0), tCK=6ns for DDR333, CL=3 at tCK=5ns for DDR400; 50% of data changing on every transfer; lout = 0 m A	IDD4R
Operating current - burst write; Burst length = 2; writes; continuous burst; One bank active address and control inputs changing once per clock cycle; CL=2 at tCK=10ns for DDR200, CL=2 at tCK=7.5ns for DDR266(A2), CL=2.5 at tCK=7.5ns for DDR266(B0), 6ns for DDR333, 5ns for DDR400; DQ, DM and DQS inputs changing twice per clock cycle, 50% of input data changing at every burst	IDD4W
Auto refresh current; tRC = tRFC(min) which is 12*tCK for DDR200 at tCK=10ns; 16*tCK for DDR266 at tCK=7.5ns; 20*tCK for DDR333 at tCK=6ns, 24*tCK for DDR400 at tCK=5ns; distributed refresh	IDD5
Self refresh current; CKE =< 0.2V; External clock on; tCK=10ns for DDR200, tCK=7.5ns for DDR266, 6ns for DDR333, 5ns for DDR400.	IDD6
Operating current - Four bank operation ; Four bank interleaving with BL=4 -Refer to the following page for detailed test condition	IDD7A

13.0 Input/Output Capacitance

(T _Δ =	25°C,	f=100MHz)

iolo input output oupuoliunoo		• •	•	,		
Parameter	Symbol	Min	Мах	DeltaCap(max)	Unit	Note
Input capacitance (A0 ~ A12, BA0 ~ BA1, CKE, CS, RAS, CAS, WE)	CIN1	2	3	0.5	pF	4
Input capacitance(CK, CK)	CIN2	2	3	0.25	pF	4
Data & DQS input/output capacitance	COUT	4	5	0.5	pF	1,2,3,4
Input capacitance(DM for x4/8, UDM/LDM for x16)	CIN3	4	5	0.5	pF	1,2,3,4

Note :

1. These values are guaranteed by design and are tested on a sample basis only.

2. Although DM is an input -only pin, the input capacitance of this pin must model the input capacitance of the DQ and DQS pins.

This is required to match signal propagation times of DQ, DQS, and DM in the system.

3. Unused pins are tied to ground.

4. This parameteer is sampled. For DDR266 and DDR333 VDDQ = +2.5V +0.2V, VDD = +3.3V +0.3V or +0.25V+0.2V. For

DDR400, VDDQ = +2.6V +0.1V, VDD = +2.6V +0.1V. For all devices, f=100MHz, tA=25°C, Vout(dc) = VDDQ/2, Vout(peak to peak) = 0.2V. DM inputs are grouped with I/O pins - reflecting the fact that they are matched in loading (to facilitate trace matching at the board level).



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14.0 Detailed test condition for DDR SDRAM IDD1 & IDD7A

IDD1 : Operating current: One bank operation

- 1. Typical Case: For DDR200,266,333: Vdd = 2.5V, T=25°C; For DDR400: Vdd=2.6V,T=25°C Worst Case : Vdd = 2.7V, T= 10°C
- 2. Only one bank is accessed with tRC(min), Burst Mode, Address and Control inputs on NOP edge are changing once per clock cycle. lout = 0mA

3. Timing patterns

- B0(133Mhz, CL=2.5) : tCK = 7.5ns, CL=2.5, BL=4, tRCD = 3*tCK, tRC = 9*tCK, tRAS = 6*tCK Read : A0 N N R0 N N P0 N N A0 N - repeat the same timing with random address changing *50% of data changing at every burst
- A2 (133Mhz, CL=2) : tCK = 7.5ns, CL=2, BL=4, tRCD = 3*tCK, tRC = 9*tCK, tRAS = 6*tCK Read : A0 N N R0 N N P0 N N A0 N - repeat the same timing with random address changing *50% of data changing at every burst
- B3(166Mhz, CL=2.5) : tCK=6ns, CL=2.5, BL=4, tRCD=3*tCK, tRC = 10*tCK, tRAS=7*tCK Read : A0 N N R0 N N P0 N N A0 N - repeat the same timing with random address changing *50% of data changing at every burst
- CC(200Mhz,CL = 3) : tCK = 5ns, CL = 3, BL = 4, tRCD = 3*tCK , tRC = 11*tCK, tRAS = 8*tCK Read : A0 N N R0 N N N P0 N N - repeat the same timing with random address changing *50% of data changing at every transfer

Legend : A=Activate, R=Read, W=Write, P=Precharge, N=DESELECT

IDD7A : Operating current: Four bank operation

- 1. Typical Case: For DDR200,266,333: Vdd = 2.5V, T=25°C; For DDR400: Vdd=2.6V,T=25°C Worst Case : Vdd = 2.7V, T= 10°C
- 2. Four banks are being interleaved with tRC(min), Burst Mode, Address and Control inputs on NOP edge are not changing. lout = 0mA
- 4. Timing patterns
- B0(133Mhz, CL=2.5) : tCK = 7.5ns, CL=2.5, BL=4, tRRD = 2*tCK, tRCD = 3*tCK, Read with autoprecharge Read : A0 N A1 R0 A2 R1 A3 R2 N R3 A0 N A1 R0 - repeat the same timing with random address changing *50% of data changing at every burst
- A2(133Mhz, CL=2) : tCK = 7.5ns, CL2=2, BL=4, tRRD = 2*tCK, tRCD = 3*tCK, Read with autoprecharge Read : A0 N A1 R0 A2 R1 A3 R2 N R3 A0 N A1 R0 - repeat the same timing with random address changing *50% of data changing at every burst
- B3(166Mhz,CL=2.5) : tCK=6ns, CL=2.5, BL=4, tRRD=2*tCK, tRCD=3*tCK, Read with autoprecharge Read : A0 N A1 R0 A2 R1 A3 R2 N R3 A0 N A1 R0 - repeat the same timing with random address changing *50% of data changing at every burst
- CC(200Mhz,CL = 3) : tCK = 5ns, CL = 3, BL = 4, tRCD = 3*tCK , tRC = 11*tCK, tRAS = 8*tCK Read : A0 N N R0 N N N P0 N N - repeat the same timing with random address changing *50% of data changing at every transfer

Legend : A=Activate, R=Read, W=Write, P=Precharge, N=DESELECT



15.0 DDR SDRAM IDD spec table

6	ymbol	64Mx4 (K	4H560438H)	Unit	Notes
3	ymbol	A2(DDR266@CL=2.0)	B0(DDR266@CL=2.5)	Onit	Notes
	IDD0	80	80	mA	
	IDD1	105	105	mA	
I	DD2P	3	3	mA	
	IDD2F 25		25	mA	
I	IDD2Q 23		23	mA	
I	IDD3P 30		30		
I	DD3N	45	45	mA	
I	DD4R	135	135	mA	
I	DD4W	135	135	mA	
	IDD5	160	160	mA	
IDD6	Normal 3		3	mA	
סטטו	Low power 1.5		1.5	mA	
IDD7A 250		250	250	mA	

	ymbol		32Mx8 (K4	H560838H)		Unit	Notes
3	ymbol	CC(DDR400@CL=3)	B3(DDR333@CL=2.5)	A2(DDR266@CL=2.0)	B0(DDR266@CL=2.5)	Unit	Notes
	IDD0	105	90	80	80	mA	
	IDD1	130	115	105	105	mA	
	IDD2P	4	3	3	3	mA	
	IDD2F	30	30	25	25	mA	
I	IDD2Q 25		25	23	23	mA	
	IDD3P 50		35	30	30	mA	
I	IDD3N	65	55	45	45	mA	
I	IDD4R	170	150	135	135	mA	
I	DD4W	170	150	135	135	mA	
	IDD5	180	170	160	160	mA	
IDD6	Normal	3	3	3	3	mA	
סטטו	Low power	1.5	1.5	1.5	1.5	mA	
I	IDD7A	300	280	250	250	mA	

6	ymbol		16Mx16 (K4	H561638H)		Unit	Notes
3	ymbol	CC(DDR400@CL=3)	B3(DDR333@CL=2.5)	A2(DDR266@CL=2.0)	B0(DDR266@CL=2.5)	Unit	NOLES
	IDD0	110	90	80	80	mA	
	IDD1	150	125	115	115	mA	
I	IDD2P	4	3	3	3	mA	
	IDD2F	30	30	25	25	mA	
IDD2Q 25		25	25	23	23	mA	
IDD3P 50		50	35	30	30	mA	
I	IDD3N	65	55	45	45	mA	
I	DD4R	180	160	155	155	mA	
I	DD4W	180	160	155	155	mA	
	IDD5	200	180	165	165	mA	
IDD6	Normal	3	3	3	3	mA	
סטטו	Low power	1.5	1.5	1.5	1.5	mA	
I	IDD7A	350	330	280	280	mA	



16.0 AC Operating Conditions

Parameter/Condition	Symbol	Min	Max	Unit	Note
Input High (Logic 1) Voltage, DQ, DQS and DM signals	VIH(AC)	VREF + 0.31		V	
Input Low (Logic 0) Voltage, DQ, DQS and DM signals.	VIL(AC)		VREF - 0.31	V	
Input Differential Voltage, CK and /CK inputs	VID(AC)	0.7	VDDQ+0.6	V	1
Input Crossing Point Voltage, CK and /CK inputs	VIX(AC)	0.5*VDDQ-0.2	0.5*VDDQ+0.2	V	2

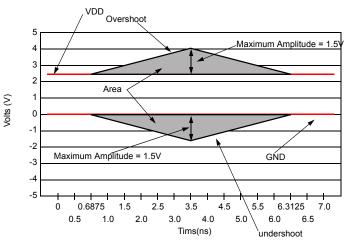
Note :

1. VID is the magnitude of the difference between the input level on CK and the input level on /CK.

2. The value of VIX is expected to equal 0.5*VDDQ of the transmitting device and must track variations in the dc level of the same.

17.0 AC Overshoot/Undershoot specification for Address and Control Pins

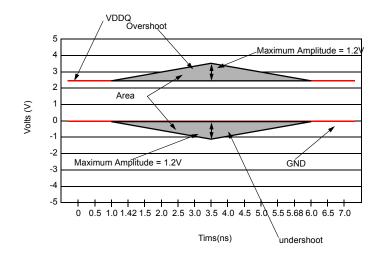
Parameter			
Falameter	DDR400	DDR333	DDR200/266
Maximum peak amplitude allowed for overshoot	1.5 V	1.5 V	1.5 V
Maximum peak amplitude allowed for undershoot	1.5 V	1.5 V	1.5 V
The area between the overshoot signal and VDD must be less than or equal to	4.5 V-ns	4.5 V-ns	4.5 V-ns
The area between the undershoot signal and GND must be less than or equal to	4.5 V-ns	4.5 V-ns	4.5 V-ns



AC overshoot/Undershoot Definition

18.0 Overshoot/Undershoot specification for Data, Strobe and Mask Pins

Parameter	Specification					
Falameter	DDR400	DDR333	DDR200/266			
Maximum peak amplitude allowed for overshoot	1.2 V	1.2 V	1.2 V			
Maximum peak amplitude allowed for undershoot	1.2 V	1.2 V	1.2 V			
The area between the overshoot signal and VDD must be less than or equal to	2.4 V-ns	2.4 V-ns	2.4 V-ns			
The area between the undershoot signal and GND must be less than or equal to	2.4 V-ns	2.4 V-ns	2.4 V-ns			



DQ/DM/DQS AC overshoot/Undershoot Definition

19.0 AC Timming Parameters & Specifications

Parameter		Symbol	C (DDR400(C @CL=3.0)	B (DDR333(3 @CL=2.5)	A (DDR266)		B (DDR266)		Unit	Note
		• • • • • • •	Min	Max	Min	Max	Min	Max	Min	Max	•••••	
Row cycle time		tRC	55		60		65		65		ns	
Refresh row cycle time		tRFC	70		72		75		75		ns	. <u></u>
Row active time		tRAS	40	70K	42	70K	45	70K	45	70K	ns	
RAS to CAS delay		tRCD	15		18		20		20		ns	
Row precharge time		tRP	15		18		20		20		ns	
Row active to Row active delay		tRRD	10		12		15		15		ns	
Write recovery time		tWR	15		15		15		15		ns	 I
Last data in to Read command		tWTR	2		1		1		1		tCK	 I
	CL=2.0		-	-	7.5	12	7.5	12	10	12	ns	
Clock cycle time	CL=2.5	tCK	6	12	6	12	7.5	12	7.5	12	ns	
	CL=3.0		5	10	-	-	-	-	-	-		
Clock high level width		tCH	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	tCK	
Clock low level width		tCL	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	tCK	
DQS-out access time from CK/C	ĸ	tDQSCK	-0.55	+0.55	-0.6	+0.6	-0.75	+0.75	-0.75	+0.75	ns	
Output data access time from Cl	K/CK	tAC	-0.65	+0.65	-0.7	+0.7	-0.75	+0.75	-0.75	+0.75	ns	 I
Data strobe edge to ouput data	edge	tDQSQ	-	0.4	-	0.45	-	0.5	-	0.5	ns	22
Read Preamble	-	tRPRE	0.9	1.1	0.9	1.1	0.9	1.1	0.9	1.1	tCK	 I
Read Postamble		tRPST	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	tCK	
CK to valid DQS-in		tDQSS	0.72	1.28	0.75	1.25	0.75	1.25	0.75	1.25	tCK	
DQS-in setup time		tWPRES	0		0		0		0		ns	13
DQS-in hold time		tWPRE	0.25		0.25		0.25		0.25		tCK	
DQS falling edge to CK rising-se	tup time	tDSS	0.2		0.2		0.2		0.2		tCK	
DQS falling edge from CK rising		tDSH	0.2		0.2		0.2		0.2		tCK	
DQS-in high level width		tDQSH	0.35		0.35		0.35		0.35		tCK	
DQS-in low level width		tDQSL	0.35		0.35		0.35		0.35		tCK	. <u></u>
Address and Control Input setup	time(fast)	tIS	0.6		0.75		0.9		0.9		ns	15, 17~19
Address and Control Input hold	time(fast)	tIH	0.6		0.75		0.9		0.9		ns	15, 17~19
Address and Control Input setup	,	tIS	0.7		0.8		1.0		1.0		ns	16~19
Address and Control Input hold t	time(slow)	tIH	0.7		0.8		1.0		1.0		ns	16~19
Data-out high impedence time fr	, ,	tHZ	-0.65	+0.65	-0.7	+0.7	-0.75	+0.75	-0.75	+0.75	ns	11
Data-out low impedence time fro		tLZ	-0.65	+0.65	-0.7	+0.7	-0.75	+0.75	-0.75	+0.75	ns	11
Mode register set cycle time		tMRD	10		12	-	15		15		ns	
DQ & DM setup time to DQS		tDS	0.4		0.45		0.5		0.5		ns	j, k
DQ & DM hold time to DQS		tDH	0.4		0.45		0.5		0.5		ns	j, k
Control & Address input pulse w	idth	tIPW	2.2		2.2		2.2		2.2		ns	18
DQ & DM input pulse width		tDIPW	1.75		1.75		1.75		1.75		ns	18
Exit self refresh to non-Read cor	mmand	tXSNR	75		75		75		75		ns	 I
Exit self refresh to read commar	nd	tXSRD	200		200		200		200		tCK	 I
Refresh interval time		tREFI		7.8		7.8		7.8		7.8	us	14
Output DQS valid window		tQH	tHP -tQHS	-	tHP -tQHS	-	tHP -tQHS	-	tHP -tQHS	-	ns	21
Clock half period		tHP	tCLmin or tCHmin	-	tCLmin or tCHmin	-	tCLmin or tCHmin	-	tCLmin or tCHmin	-	ns	20, 21
Data hold skew factor		tQHS		0.5		0.55		0.75		0.75	ns	21
DQS write postamble time		tWPST	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	tCK	12
Active to Read with Auto precha command	rge	tRAP	15		18		20		20			
Autoprecharge write recovery + Precharge time		tDAL	(tWR/tCK) + (tRP/tCK)		(tWR/tCK) + (tRP/tCK)		(tWR/tCK) + (tRP/tCK)		(tWR/tCK) + (tRP/tCK)		tCK	23
Power Down Exit Time		tPDEX	1		1		1		1		tCK	·
· · · · · · · · · · · · · · · · · · ·			1		1		1		1			

20.0 System Characteristics for DDR SDRAM

The following specification parameters are required in systems using DDR400, DDR333 & DDR266 devices to ensure proper system performance. these characteristics are for system simulation purposes and are guaranteed by design.

Table 1 : Input Slew Rate for DQ, DQS, and DM

AC CHARACTERISTICS		DDF	R400	DDF	333	DDF	R266		
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX	MIN	MAX	Units	Notes
DQ/DM/DQS input slew rate measured between VIH(DC), VIL(DC) and VIL(DC), VIH(DC)	DCSLEW	0.5	4.0	0.5	4.0	0.5	4.0	V/ns	a, I

Table 2 : Input Setup & Hold Time Derating for Slew Rate

Input Slew Rate	∆tIS	∆tIH	Units	Notes				
0.5 V/ns	0	0	ps	i				
0.4 V/ns	+50	0	ps	i				
0.3 V/ns	+100	0	ps	i				

Table 3 : Input/Output Setup & Hold Time Derating for Slew Rate

Input Slew Rate	∆tDS	∆tDH	Units	Notes
0.5 V/ns	0	0	ps	k
0.4 V/ns	+75	+75	ps	k
0.3 V/ns	+150	+150	ps	k

Table 4 : Input/Output Setup & Hold Derating for Rise/Fall Delta Slew Rate

Delta Slew Rate	∆tDS	∆tDH	Units	Notes
+/- 0.0 V/ns	0	0	ps	j
+/- 0.25 V/ns	+50	+50	ps	j
+/- 0.5 V/ns	+100	+100	ps	j

Table 5 : Output Slew Rate Characteristice (X4, X8 Devices only)

Slew Rate Characteristic	Typical Range (V/ns)	Minimum (V/ns)	Maximum (V/ns)	Notes	
Pullup Slew Rate	1.2 ~ 2.5	1.0	4.5	a,c,d,f,g,h	
Pulldown slew	1.2 ~ 2.5	1.0	4.5	b,c,d,f,g,h	

Table 6 : Output Slew Rate Characteristice (X16 Devices only)

Slew Rate Characteristic	Typical Range (V/ns)	Minimum (V/ns)	Maximum (V/ns)	Notes	
Pullup Slew Rate	1.2 ~ 2.5	0.7	5.0	a,c,d,f,g,h	
Pulldown slew	1.2 ~ 2.5	0.7	5.0	b,c,d,f,g,h	

Table 7 : Output Slew Rate Matching Ratio Characteristics

AC CHARACTERISTICS		DDR400		DDR333		R266	
PARAMETER		MAX	MIN	MAX	MIN	MAX	Notes
Output Slew Rate Matching Ratio (Pullup to Pulldown)	0.67	1.5	0.67	1.5	0.67	1.5	e, l



21.0 Component Notes

- 1. All voltages referenced to Vss.
- 2. Tests for ac timing, IDD, and electrical, ac and dc characteristics, may be conducted at nominal reference/supply voltage levels, but the related specifications and device operation are guaranteed for the full voltage range specified.
- 3. Figure 1 represents the timing reference load used in defining the relevant timing parameters of the part. It is not intended to be either a precise representation of the typical system environment nor a depiction of the actual load presented by a production tester. System designers will use IBIS or other simulation tools to correlate the timing reference load to a system environment. Manufacturers will correlate to their production test conditions (generally a coaxial transmission line terminated at the tester electronics).

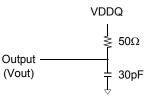


Figure 1 : Timing Reference Load

- 4. AC timing and IDD tests may use a VIL to VIH swing of up to 1.5 V in the test environment, but input timing is still referenced to VREF (or to the crossing point for CK/CK), and parameter specifications are guaranteed for the specified ac input levels under normal use conditions. The minimum slew rate for the input signals is 1 V/ns in the range between VIL(ac) and VIH(ac).
- 5. The ac and dc input level specifications are as defined in the SSTL_2 Standard (i.e., the receiver will effectively switch as a result of the signal crossing the ac input level and will remain in that state as long as the signal does not ring back above (below) the dc input LOW (HIGH) level.
- 6. Inputs are not recognized as valid until VREF stabilizes. Exception: during the period before VREF stabilizes, CKE ≤ 0.2VDDQ is recognized as LOW.
- 7. Enables on chip refresh and address counters.
- 8. IDD specifications are tested after the device is properly initialized.
- 9. The CK/CK input reference level (for timing referenced to CK/CK) is the point at which CK and CK cross; the input reference level for signals other than CK/CK, is VREF.
- 10. The output timing reference voltage level is VTT.
- 11. tHZ and tLZ transitions occur in the same access time windows as valid data transitions. These parameters are not referenced to a specific voltage level but specify when the device output is no longer driving (HZ), or begins driving (LZ).
- 12. The maximum limit for this parameter is not a device limit. The device will operate with a greater value for this parameter, but sys tem performance (bus turnaround) will degrade accordingly.
- 13. The specific requirement is that DQS be valid (HIGH, LOW, or at some point on a valid transition) on or before this CK edge. A valid transition is defined as monotonic and meeting the input slew rate specifications of the device. when no writes were previously in progress on the bus, DQS will be transitioning from High-Z to logic LOW. If a previous write was in progress, DQS could be HIGH, LOW, or transitioning from HIGH to LOW at this time, depending on tDQSS.
- 14. A maximum of eight AUTO REFRESH commands can be posted to any given DDR SDRAM device.
- 15. For command/address input slew rate \geq 1.0 V/ns
- 16. For command/address input slew rate \geq 0.5 V/ns and <~ 1.0 V/ns



Component Notes

- 17. For CK & \overline{CK} slew rate ≥ 1.0 V/ns
- 18. These parameters guarantee device timing, but they are not necessarily tested on each device. They may be guaranteed by device design or tester correlation.
- 19. Slew Rate is measured between VOH(ac) and VOL(ac).
- 20. Min (tCL, tCH) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for tCL and tCH).....For example, tCL and tCH are = 50% of the period, less the half period jitter (tJIT(HP)) of the clock source, and less the half period jitter due to crosstalk (tJIT(crosstalk)) into the clock traces.
- 21. tQH = tHP tQHS, where:

tHP = minimum half clock period for any given cycle and is defined by clock high or clock low (tCH, tCL). tQHS accounts for 1) The pulse duration distortion of on-chip clock circuits; and 2) The worst case push-out of DQS on one tansition followed by the worst case pull-in of DQ on the next transition, both of which are, separately, due to data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers.

22. tDQSQ

Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers for any given cycle.

23. tDAL = (tWR/tCK) + (tRP/tCK)

For each of the terms above, if not already an integer, round to the next highest integer. Example: For DDR266B at CL=2.5 and tCK=7.5ns tDAL = (15 ns / 7.5 ns) + (20 ns/ 7.5ns) = (2) + (3) tDAL = 5 clocks



22.0 System Notes

a. Pullup slew rate is characteristized under the test conditions as shown in Figure 2.

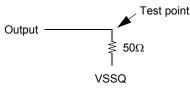


Figure 2 : Pullup slew rate test load

b. Pulldown slew rate is measured under the test conditions shown in Figure 3.

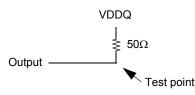


Figure 3 : Pulldown slew rate test load

c. Pullup slew rate is measured between (VDDQ/2 - 320 mV +/- 250 mV)

Pulldown slew rate is measured between (VDDQ/2 + 320 mV +/- 250 mV) Pullup and Pulldown slew rate conditions are to be met for any pattern of data, including all outputs switching and only one output

- switching.
- Example : For typical slew rate, DQ0 is switching

For minmum slew rate, all DQ bits are switching from either high to low, or low to high.

The remaining DQ bits remain the same as for previous state.

d. Evaluation conditions

Typical : 25 °C (T Ambient), VDDQ = 2.5V(for DDR266/333) and 2.6V(for DDR400), typical process Minimum : 70 °C (T Ambient), VDDQ = 2.3V(for DDR266/333) and 2.5V(for DDR400), slow - slow process Maximum : 0 °C (T Ambient), VDDQ = 2.7V(for DDR266/333) and 2.7V(for DDR400), fast - fast process

- e. The ratio of pullup slew rate to pulldown slew rate is specified for the same temperature and voltage, over the entire temperature and voltage range. For a given output, it represents the maximum difference between pullup and pulldown drivers due to process variation.
- f. Verified under typical conditions for qualification purposes.
- g. TSOPII package divices only.
- h. Only intended for operation up to 400 Mbps per pin.
- i. A derating factor will be used to increase tIS and tIH in the case where the input slew rate is below 0.5V/ns as shown in Table 2. The Input slew rate is based on the lesser of the slew rates detemined by either VIH(AC) to VIL(AC) or VIH(DC) to VIL(DC), similarly for rising transitions.

j. A derating factor will be used to increase tDS and tDH in the case where DQ, DM, and DQS slew rates differ, as shown in Tables 3 & 4. Input slew rate is based on the larger of AC-AC delta rise, fall rate and DC-DC delta rise, Input slew rate is based on the lesser of the slew rates determined by either VIH(AC) to VIL(AC) or VIH(DC) to VIL(DC), similarly for rising transitions. The delta rise/fall rate is calculated as: {1/(Slew Rate1)} - {1/(Slew Rate2)}

For example : If Slew Rate 1 is 0.5 V/ns and slew Rate 2 is 0.4 V/ns, then the delta rise, fall rate is - 0.5ns/V. Using the table given, this would result in the need for an increase in tDS and tDH of 100 ps.

- k. Table 3 is used to increase tDS and tDH in the case where the I/O slew rate is below 0.5 V/ns. The I/O slew rate is based on the lesser on the lesser of the AC - AC slew rate and the DC- DC slew rate. The inut slew rate is based on the lesser of the slew rates deter mined by either VIH(ac) to VIL(ac) or VIH(DC) to VIL(DC), and similarly for rising transitions.
- I. DQS, DM, and DQ input slew rate is specified to prevent double clocking of data and preserve setup and hold times. Signal transi tions through the DC region must be monotonic.

SAMSUNG

23.0 IBIS : I/V Characteristics for Input and Output Buffers

DDR SDRAM Output Driver V-I Characteristics

DDR SDRAM Output driver characteristics are defined for full and half strength operation as selected by the EMRS bit A1.

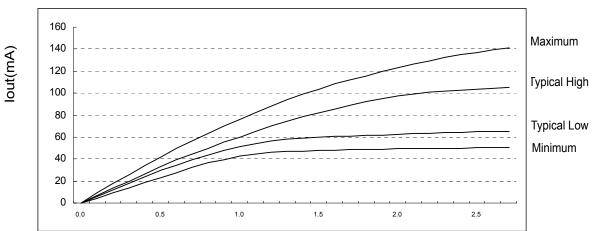
Figures 3 and 4 show the driver characteristics graphically, and tables 8 and 9 show the same data in tabular format suitable for input

into simulation tools. The driver characteristcs evaluation conditions are:

Typical	25×C	Vdd/Vddq = 2.5V, typical process
Minimum	70×C	Vdd/Vddq = 2.3V, slow-slow process
Maximum	0×C	Vdd/Vddq = 2.7V, fast-fast process

Output Driver Characteristic Curves Notes:

- 1. The full variation in driver current from minimum to maximum process, temperature and voltage will lie within the outer bounding lines the of the V-I curve of Figure 3 and 4.
- 2. It is recommended that the "typical" IBIS V-I curve lie within the inner bounding lines of the V-I curves of Figure 3 and 4.
- 3. The full variation in the ratio of the "typical" IBIS pullup to "typical" IBIS pulldown current should be unity +/- 10%, for device drain to source voltages from 0.1 to1.0. This specification is a design objective only. It is not guaranteed.



Pullup Characteristics for Full Strength Output Driver Vout(V)

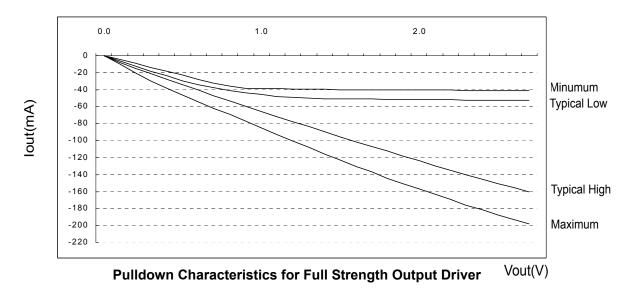


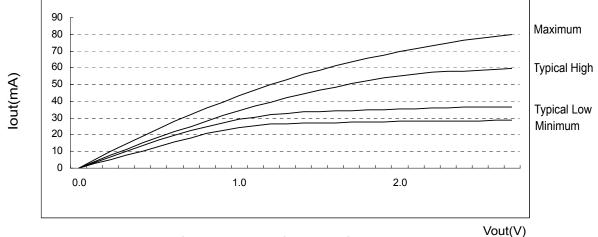
Figure 3. I/V characteristics for input/output buffers:Pull up(above) and pull down(below)

	Pulldown Current (mA)				pullup Current (mA)			
Voltage (V)	Typical Low	Typical High	Minimum	Maximum	Typical Low	Typical High	Minimum	Maximum
0.1	6.0	6.8	4.6	9.6	-6.1	-7.6	-4.6	-10.0
0.2	12.2	13.5	9.2	18.2	-12.2	-14.5	-9.2	-20.0
0.3	18.1	20.1	13.8	26.0	-18.1	-21.2	-13.8	-29.8
0.4	24.1	26.6	18.4	33.9	-24.0	-27.7	-18.4	-38.8
0.5	29.8	33.0	23.0	41.8	-29.8	-34.1	-23.0	-46.8
0.6	34.6	39.1	27.7	49.4	-34.3	-40.5	-27.7	-54.4
0.7	39.4	44.2	32.2	56.8	-38.1	-46.9	-32.2	-61.8
0.8	43.7	49.8	36.8	63.2	-41.1	-53.1	-36.0	-69.5
0.9	47.5	55.2	39.6	69.9	-41.8	-59.4	-38.2	-77.3
1.0	51.3	60.3	42.6	76.3	-46.0	-65.5	-38.7	-85.2
1.1	54.1	65.2	44.8	82.5	-47.8	-71.6	-39.0	-93.0
1.2	56.2	69.9	46.2	88.3	-49.2	-77.6	-39.2	-100.6
1.3	57.9	74.2	47.1	93.8	-50.0	-83.6	-39.4	-108.1
1.4	59.3	78.4	47.4	99.1	-50.5	-89.7	-39.6	-115.5
1.5	60.1	82.3	47.7	103.8	-50.7	-95.5	-39.9	-123.0
1.6	60.5	85.9	48.0	108.4	-51.0	-101.3	-40.1	-130.4
1.7	61.0	89.1	48.4	112.1	-51.1	-107.1	-40.2	-136.7
1.8	61.5	92.2	48.9	115.9	-51.3	-112.4	-40.3	-144.2
1.9	62.0	95.3	49.1	119.6	-51.5	-118.7	-40.4	-150.5
2.0	62.5	97.2	49.4	123.3	-51.6	-124.0	-40.5	-156.9
2.1	62.9	99.1	49.6	126.5	-51.8	-129.3	-40.6	-163.2
2.2	63.3	100.9	49.8	129.5	-52.0	-134.6	-40.7	-169.6
2.3	63.8	101.9	49.9	132.4	-52.2	-139.9	-40.8	-176.0
2.4	64.1	102.8	50.0	135.0	-52.3	-145.2	-40.9	-181.3
2.5	64.6	103.8	50.2	137.3	-52.5	-150.5	-41.0	-187.6
2.6	64.8	104.6	50.4	139.2	-52.7	-155.3	-41.1	-192.9
2.7	65.0	105.4	50.5	140.8	-52.8	-160.1	-41.2	-198.2

Table 8. Full Strength Driver Characteristics

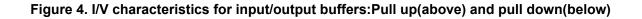


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Pullup Characteristics for Weak Output Driver







	Pulldown Current (mA)				pullup Current (mA)			
Voltage (V)	Typical Low	Typical High	Minimum	Maximum	Typical Low	Typical High	Minimum	Maximum
0.1	3.4	3.8	2.6	5.0	-3.5	-4.3	-2.6	-5.0
0.2	6.9	7.6	5.2	9.9	-6.9	-8.2	-5.2	-9.9
0.3	10.3	11.4	7.8	14.6	-10.3	-12.0	-7.8	-14.6
0.4	13.6	15.1	10.4	19.2	-13.6	-15.7	-10.4	-19.2
0.5	16.9	18.7	13.0	23.6	-16.9	-19.3	-13.0	-23.6
0.6	19.6	22.1	15.7	28.0	-19.4	-22.9	-15.7	-28.0
0.7	22.3	25.0	18.2	32.2	-21.5	-26.5	-18.2	-32.2
0.8	24.7	28.2	20.8	35.8	-23.3	-30.1	-20.4	-35.8
0.9	26.9	31.3	22.4	39.5	-24.8	-33.6	-21.6	-39.5
1.0	29.0	34.1	24.1	43.2	-26.0	-37.1	-21.9	-43.2
1.1	30.6	36.9	25.4	46.7	-27.1	-40.3	-22.1	-46.7
1.2	31.8	39.5	26.2	50.0	-27.8	-43.1	-22.2	-50.0
1.3	32.8	42.0	26.6	53.1	-28.3	-45.8	-22.3	-53.1
1.4	33.5	44.4	26.8	56.1	-28.6	-48.4	-22.4	-56.1
1.5	34.0	46.6	27.0	58.7	-28.7	-50.7	-22.6	-58.7
1.6	34.3	48.6	27.2	61.4	-28.9	-52.9	-22.7	-61.4
1.7	34.5	50.5	27.4	63.5	-28.9	-55.0	-22.7	-63.5
1.8	34.8	52.2	27.7	65.6	-29.0	-56.8	-22.8	-65.6
1.9	35.1	53.9	27.8	67.7	-29.2	-58.7	-22.9	-67.7
2.0	35.4	55.0	28.0	69.8	-29.2	-60.0	-22.9	-69.8
2.1	35.6	56.1	28.1	71.6	-29.3	-61.2	-23.0	-71.6
2.2	35.8	57.1	28.2	73.3	-29.5	-62.4	-23.0	-73.3
2.3	36.1	57.7	28.3	74.9	-29.5	-63.1	-23.1	-74.9
2.4	36.3	58.2	28.3	76.4	-29.6	-63.8	-23.2	-76.4
2.5	36.5	58.7	28.4	77.7	-29.7	-64.4	-23.2	-77.7
2.6	36.7	59.2	28.5	78.8	-29.8	-65.1	-23.3	-78.8
2.7	36.8	59.6	28.6	79.7	-29.9	-65.8	-23.3	-79.7

Table 9. Weak Driver Characteristics



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